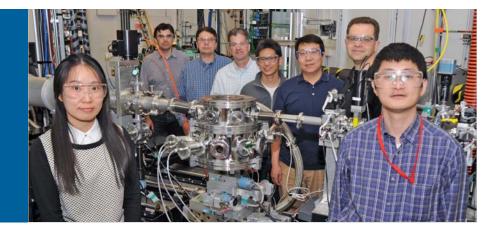


### 8-ID-E MULTI-SAMPLE GIXS VACUUM CHAMBER



JOE STRZALKA XSD-Dynamics and Structure strzalka@anl.gov 2-0283



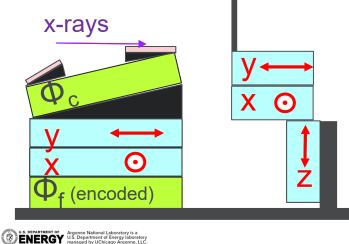
**ZHANG JIANG, JIN WANG RAY ZIEGLER** XSD-DYS and XSD-TRR MIKE FISHER XSD-BI

WEI CHEN, PAUL NEALEY ANL-MSD and CME

PUP 34174, 2013-2015

#### Vaccum (10<sup>-3</sup> torr) environment with azimuthal rotation for 8 samples

- Sample-selection rotation stage on wedge: 1 sample in beam
- Sample x-y motion and > 90° rotation
- Internal beamstop with x-y-z motion





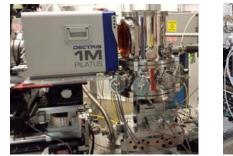


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#### Large, versatile vacuum environment(s) with top hat design

- Base chamber for all stages and feedthroughs
  - 12" flange base chamber, 10 x KF-50 flanges
- Top chambers for GISAXS/GIWAXS, more ports
  - 10" flange top chamber,
  - GISAXS: KF-50 exit, 7 x KF-40
  - GIWAXS: 8" flange exit, 6 x KF-40
- Can also operate with He, N<sub>2</sub>
  - O<sub>2</sub> sensor (Qubit S101)
  - Pressure relief valve
  - (Accu Glass 113160)

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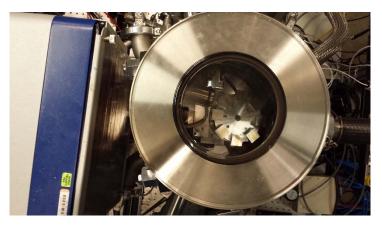




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#### **Sample considerations**

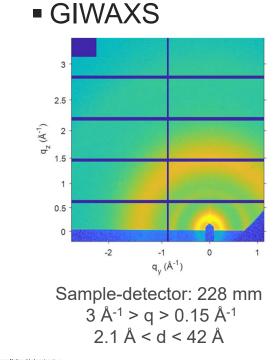
- Samples up to 24 mm x 24 mm
- Mounting samples with grease (Apiezon H/N)
- Glass viewport on lid/overhead webcam





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### Accessible Q-ranges

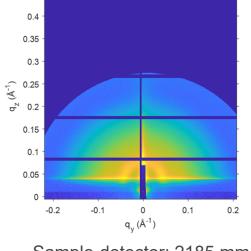


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Data courtesy of Wei Chen, ANL

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GISAXS



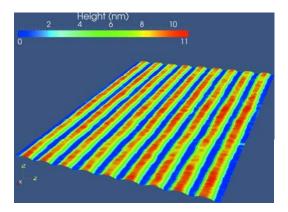
Sample-detector: 2185 mm 0.21 Å<sup>-1</sup> > q > 0.005 Å<sup>-1</sup> 29.9 Å < d < 1260 Å

Data courtesy of Ting Xu, UC Berkeley



#### **Application: Nanolithography metrology**

 Develop GISAXS as metrology tool for advanced nanolithographic technique: Directed self assembly



Suh, Chen, Rincon-Delgadillo, Jiang, Strzalka, Wang, Chen, Gronheid, de Pablo, Ferrier, Doxastakis, Nealey J Appl Cryst 49 823-834 (2016)

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